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| Notice of References Cited | Application/Control No. 10/820,294 | | Applicant(s)/Patent Under Reexamination LEE ET AL. | |
| | Examiner Andrew Schechter | | Art Unit 2871 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-6,335,775 | 01-2002 | Iwamura et al. | 349/125 |
| * | B | US-6,549,256 | 04-2003 | Bryan-Brown et al. | 349/128 |
| * | C | US-6,476,894 | 11-2002 | Kikkawa, Hironori | 349/123 |
| * | D | US-6,549,257 | 04-2003 | Liu, Hong-Da | 349/129 |
| * | E | US-6,567,144 | 05-2003 | Kim et al. | 349/128 |
| * | F | US-6,753,551 | 06-2004 | Cheng, Hsin-An | 257/79 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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